

Notice of References Cited

Application/Control No.

10/580,997

Applicant(s)/Patent Under
Reexamination
MADAR ET AL.

Examiner

MICHAEL R. VAUGHAN

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0037459 A1	11-2001	Ogawa et al.	713/200
*	B	US-2002/0126983 A1	09-2002	Sato et al.	386/46
*	C	US-2003/0126596 A1	07-2003	Kim, Eun-Mi	725/30
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003068020 A	03-2003	Japan	IWAHANA, TOSHIKI	
	O	JP 2003132624 A	05-2003	Japan	TSURUI, TAISUKE	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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